

INSULATED GATE BIPOLAR TRANSISTOR

$$V_{CES} = 1200V$$

$$I_{C(Nominal)} = 35A$$

$$T_{J(max)} = 175^{\circ}C$$

$$V_{CE(on)} typ = 1.9V @ I_{C} = 35A$$

G L E n-channel

G C E Gate Collector Emitter

Applications

- Medium Power Drives
- UPS
- HEV Inverter
- Welding
- Induction Heating

Features —	→ Benefits
	High efficiency in a wide range of applications and switching frequencies
	Improved Reliability due to rugged hard switching performance and higher power capability
Positive V _{CE (ON)} Temperature Coefficient	Excellent current sharing in parallel operation

Boss port number	Dookogo Typo	Standa	rd Pack	Ordereble next number	
Base part number	Package Type	Form	Quantity	Orderable part number	
IRG7CH50K10EF	Die on Film	Wafer	1	IRG7CH50K10EF	

Mechanical Parameter

Die Size	6.557 x 6.557	mm ²			
Minimum Street Width	75	μm			
Emiter Pad Size (Included Gate Pad)	See Die Drawing				
Gate Pad Size	1.0053 x 0.7035	mm ²			
Area Total / Active	43 x 28.02				
Thickness	140	μm			
Wafer Size	200	mm			
Notch Position	0	Degrees			
Maximum-Possible Chips per Wafer	623 pcs.	·			
Passivation Front side	Silicon Nitride	Silicon Nitride			
Front Metal	Al, Si (4μm)	Al, Si (4µm)			
Backside Metal	Al (1kA°), Ti (1kA°), Ni (4kA°), Ag (6kA°)				
Die Bond	Electrically conductive epoxy	Electrically conductive epoxy or solder			
Reject Ink Dot Size	0.25 mm diameter minimum				



Maximum Ratings

	Parameter	Max.	Units
V_{CE}	Collector-Emitter Voltage, T _J =25°C	1200	V
I _C	DC Collector Current	①	Α
I _{LM}	Clamped Inductive Load Current ®	140	Α
$V_{\sf GE}$	Gate Emitter Voltage	± 30	V
T _J , T _{STG}	Operating Junction and Storage Temperature	-40 to +175	°C

Static Characteristics (Tested on wafers) . T_J=25°C

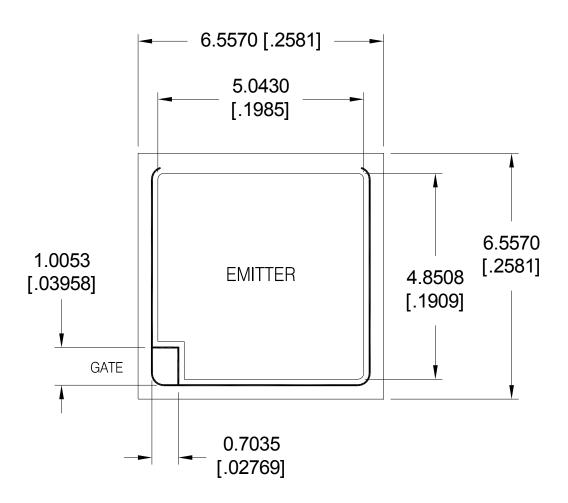
	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)CES}	Collector-to-Emitter Breakdown Voltage	1200			V	V _{GE} = 0V, I _C = 250μA ⑤
V _{CE(sat)}	Collector-to-Emitter Saturated Voltage		1.95	2.2		$V_{GE} = 15V, I_C = 25A, T_J = 25^{\circ}C$
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	5.0		7.5		$I_C = 1.7 \text{mA}$, $V_{GE} = V_{CE}$
I _{CES}	Zero Gate Voltage Collector Current		1.0	25	μΑ	V _{CE} = 1200V, V _{GE} = 0V
I _{GES}	Gate Emitter Leakage Current			± 100	nA	$V_{CE} = 0V$, $V_{GE} = \pm 30V$

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{CE(sat)}	Collector-to-Emitter Saturated Voltage		1.9	2.3	V	V _{GE} = 15V, I _C = 35A , T _J = 25°C
			2.5			V _{GE} = 15V, I _C = 35A , T _J = 175°C
SCSOA	Short Circuit Safe Operating Area	10				V _{GE} =15V, V _{CC} =600V, ② R _G =10Ω, V _P ≤1200V,T _J =150°C
RBSOA	Reverse Bias Safe Operating Area	FULL SQUARE				$T_J = 175^{\circ}C$, $I_C = 140A$ $V_{CC} = 960V$, $Vp \le 1200V$ $Rg = 10\Omega$, $V_{GE} = +20V$ to $0V$
C _{iss}	Input Capacitance		4120		pF	V _{GE} = 0V
Coss	Output Capacitance		160			V _{CE} = 30V
C _{rss}	Reverse Transfer Capacitance		100			f = 1.0MHz
Q_g	Total Gate Charge (turn-on)	_	170	_	nC	I _C = 35A ⑥
Q_{ge}	Gate-to-Emitter Charge (turn-on)	_	40	_		V _{GE} = 15V
Q_{gc}	Gate-to-Collector Charge (turn-on)		80			V _{CC} = 600V

	Parameter	Min.	Тур.	Max.	Units	Conditions ③
$t_{d(on)}$	Turn-On delay time	_	50	_		$I_C = 35A, V_{CC} = 600V$
t _r	Rise time	_	80	_		$R_G = 10\Omega$, $V_{GE}=15V$, $L=200\mu H$
$t_{d(off)}$	Turn-Off delay time		280	_		$T_J = 25^{\circ}C$
t_{f}	Fall time		30	_	no	
$t_{d(on)}$	Turn-On delay time	_	50	_		$I_C = 35A, V_{CC} = 600V$
t _r	Rise time		70	_		$R_G = 10\Omega$, $V_{GE} = 15V$, $L = 200\mu H$
$t_{d(off)}$	Turn-Off delay time		340	_		T _J = 175°C
t_f	Fall time	_	295	_		



Die Drawing



NOTES:

- 1. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 2. CONTROLLING DIMENSION: INCHES
- 3. DIE WIDTH AND LENGTH TOLERANCE: -0.0508 [.002]
- 4. DIE THICKNESS = 0.140 [.0055]

REFERENCE: IRG7CH50K10B

Notes:

- \odot The current in the application is limited by T_{JMax} and the thermal properties of the assembly.
- ② Not subject to production test- Verified by design / characterization.
- 3 Values influenced by parasitic L and C in measurement.
- $^{\circ}$ V_{CC} = 80% (V_{CES}), V_{GE} = 20V, L = 25μH, R_G = 10Ω.
- S Refer to AN-1086 for guidelines for measuring V_{(BR)CES} safely
- 6 Die Level Characterization.



Additional Testing and Screening

For Customers requiring product supplied as Known Good Die (KGD) or requiring specific die level testing, please contact your local IR Sales.

Shipping

Sawn Wafer on Film. Please contact your local IR sales office for non-standard shipping options

Handling

- Product must be handled only at ESD safe workstations. Standard ESD precautions and safe work environments are as defined in MIL-HDBK-263.
- Product must be handled only in a class 10,000 or better-designated clean room environment.
- Singulated die are not to be handled with tweezers. A vacuum wand with a non-metallic ESD protected tip should be used.

Wafer/Die Storage

- Proper storage conditions are necessary to prevent product contamination and/or degradation after shipment.
- Note: To reduce the risk of contamination or degradation, it is recommended that product not being used in the
 assembly process be returned to their original containers and resealed with a vacuum seal process.
- Sawn wafers on a film frame are intended for immediate use and have a limited shelf life.

Further Information

For further information please contact your local IR Sales office or email your enquiry to http://die.irf.com

Data and specifications subject to change without notice. This product has been designed and qualified for Industrial market.

Qualification Standards can be found on IR's Web site.



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Visit us at www.irf.com for sales contact information.

单击下面可查看定价,库存,交付和生命周期等信息

>>Infineon Technologies(英飞凌)